

QA is organized to allow essential acceptance tests on 100% of components plus in-depth sample characterization

QA stations organized in order to

Be close to the assembling site

Ensure adequate personnel training

Provide redundancy & investment synergy

Support specific in-deep characterization studies

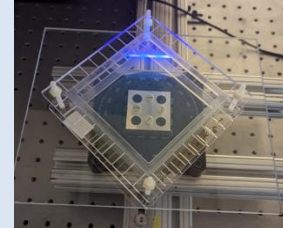
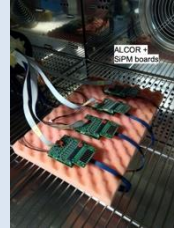
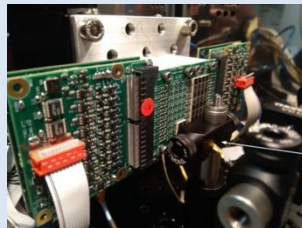
Aerogel: Integrity, defects, transmittance, refractive index, dimensions, planarity

Mirror: Dimensions, shape accuracy, radius, reflectivity

Sensors: Electrical connections, quench resistor, I-V characteristics, DCR, relative PDE

Readout: Electrical connections, bias levels, threshold and gain scans, time jitter, DAQ rate

Gas: Refractive index, transparency, sound speed, leakage rate

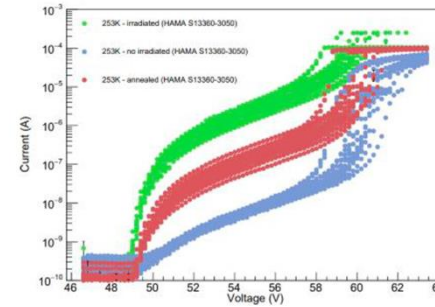


Component	QA station 1	QA station 2	QA detail and backup	QA Acceptance	In-depth
Aerogel	Temple U.	BNL	INFN-BA	100 %	5%
Gas	BNL		INFN-TS	2 %	2%
Mirror	JLab	Duke U.		100 %	10%
Sensor (SiPM)	INFN CS-SA-CT	INFN-TS	INFN-BO	100 %	1%
Readout	INFN-BO	INFN-FE	INFN-TO	100 %	1%

ALCOR based QA stations developed at INFN CS-SA-CT and INFN TS in collaboration with local Universities



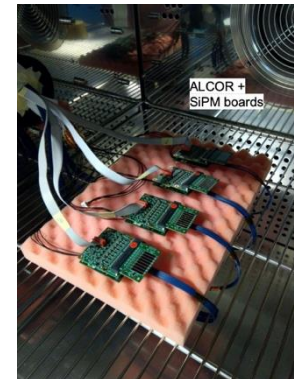
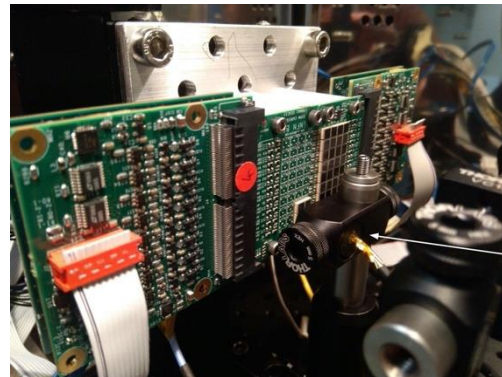
IV-curves



- 253K-blue irradiated
- 253K-annealed
- 253K-irradiated



In-depth characterization station stays operative at INFN-BO: e.g. PDE, Timing



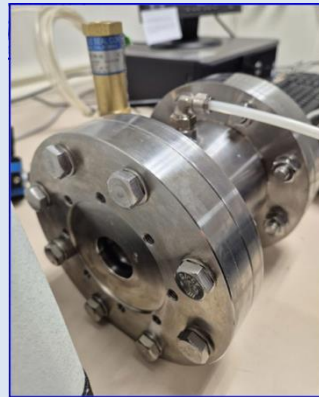
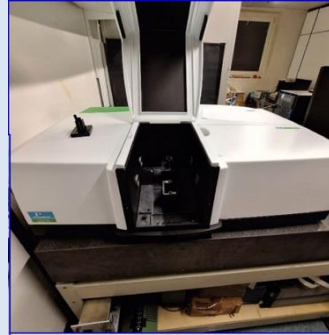
- **Spectrophotometer:** monitor of gas transparency
 - A cell of 10 cm length can be used → need to enhance the absorption by pressure: **measure at 10 bar**
 - **A stable optical table** needed to ensure correct spectrophotometer performance

- **Sonar system:** measuring the fraction of standby-gas in the vessel atmosphere (particularly relevant during filling and gas recovery)

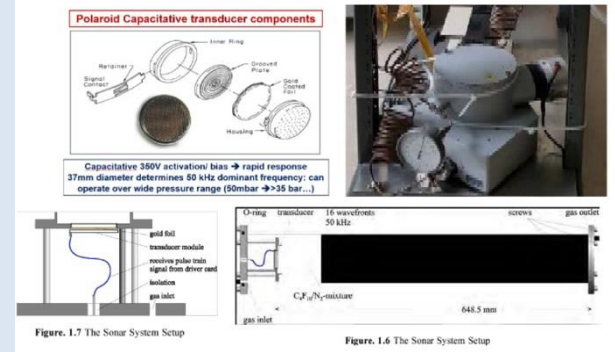
Measured speed of sound in C_2F_6 : 139.68 m/s

- **Interferometer:** real-time measurement of the refractive index (interferometer response combined with T and P monitors allows for quasi real-time data processing)
 - As for the spectrophotometer, **a stable optical table** needed to ensure the stability and preserve the alignment of the optical components

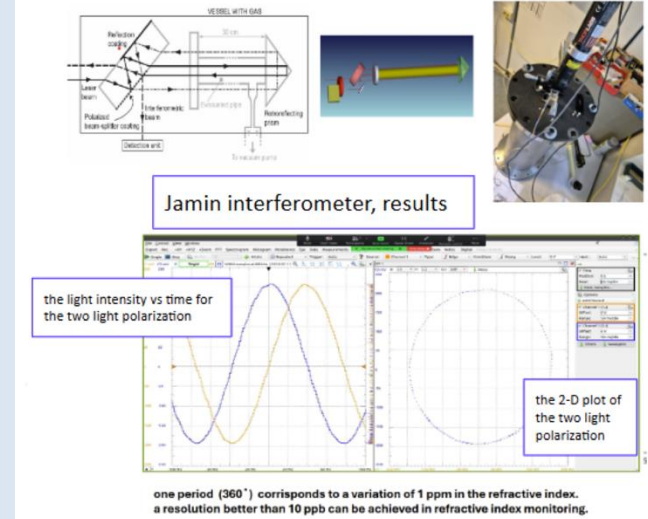
Spectrophotometer



Sonar

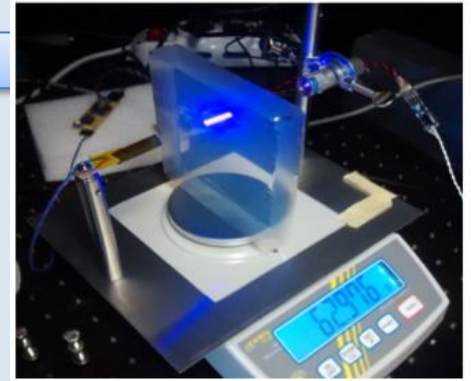


Interferometer



OPTICAL (example)

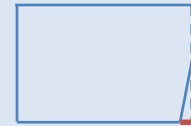
Density	$0.0926 < \rho < 1.00$	gr/cm ³
Refractive index ($n^2=1+0.27 \rho$)	$1.025 < n < 1.027$	
Scattering length	$L_{sc} > 45$	mm
Absorption coefficient	$A > 0.95$	



MECHANICAL (example)

No bubbles, crackes; chips limited to less than 1 % area

Side to side length variation $\Delta L_{side} < 0.25$ mm



Tile to tile thickness variation $\Delta H_{tile} < 1.5$ mm

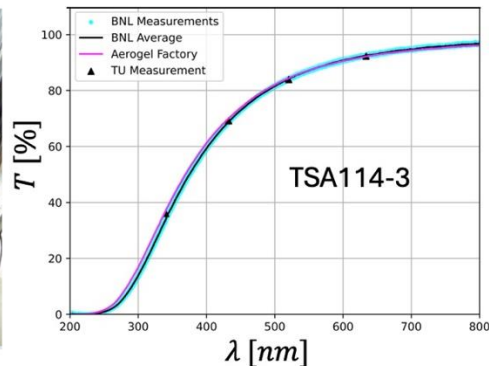
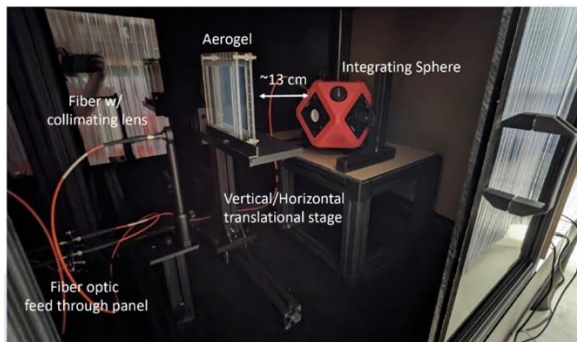


Surface planarity $\Delta S_{surf} < 1$ % of lateral side



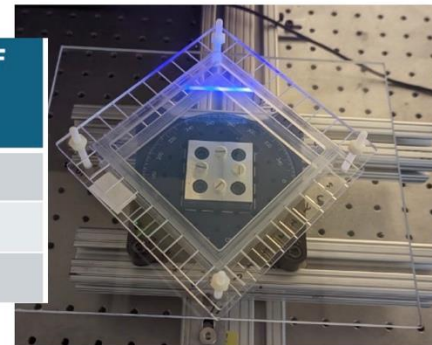
Primary station at Temple University developed as a common facility

Transmission by LEDs + Integrating sphere – Temple U.



Refractive index by Prisma test – Temple U.

Tile	(TU-AF)/AF [%]
TSA120-1	0.087
TSA120-2	0.000
TSA114-3	0.062



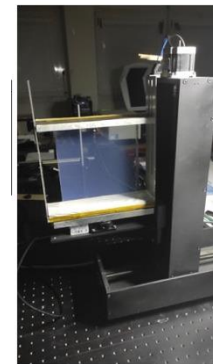
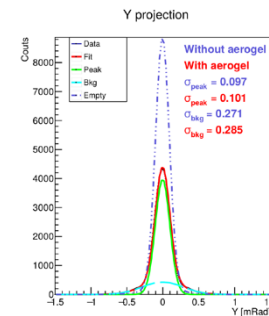
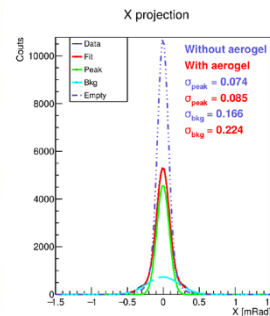
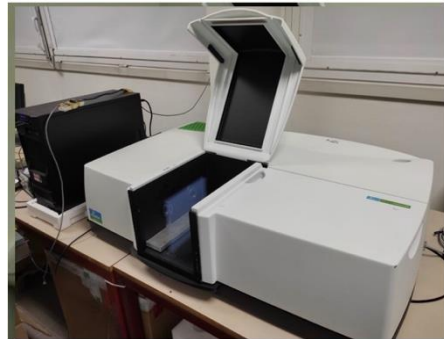
Secondary station at INFN (BA-FE) available for sample tests or in-depth characterization

Perkin Elmer 650S (INFN FE)

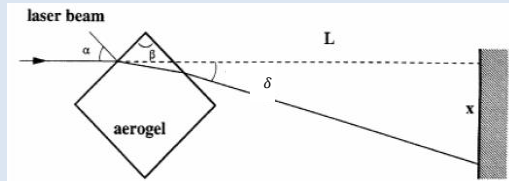
Transmission by Spectro-photometers

Agilent Cary (INFN BA)

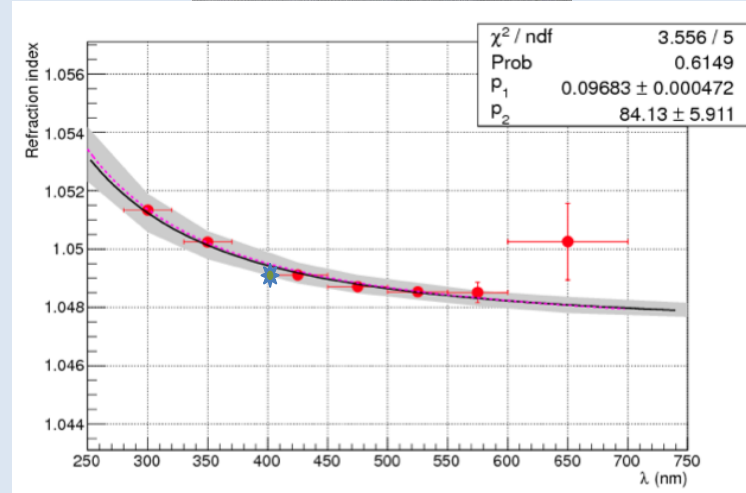
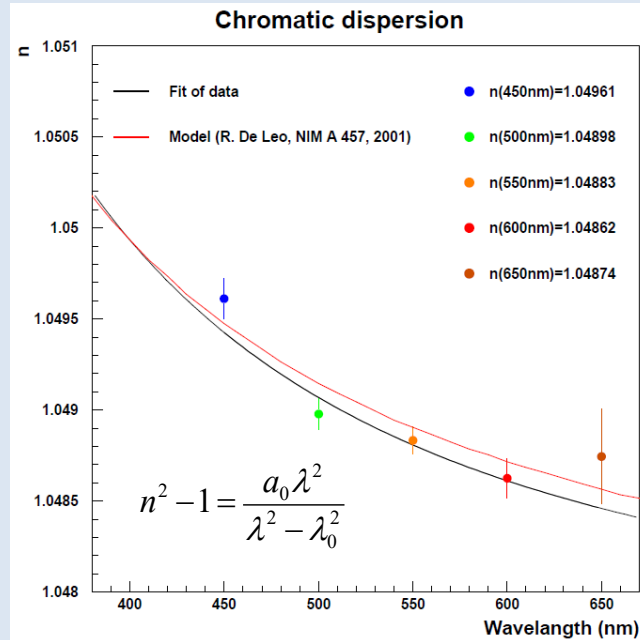
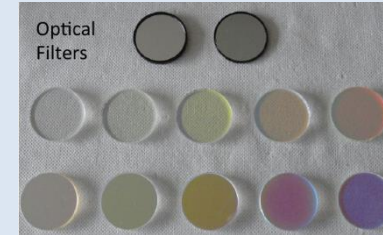
Forward Scattering by Laser + CMOS camera



Measured by prisma method:

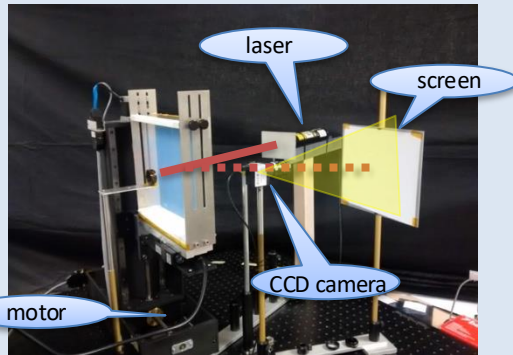
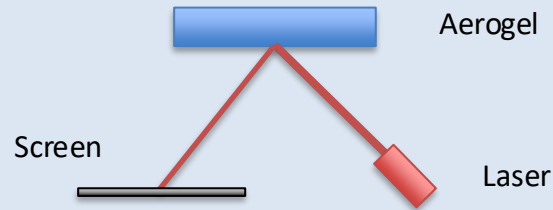


Measured by prototype with optical filters:



Expected value from density:

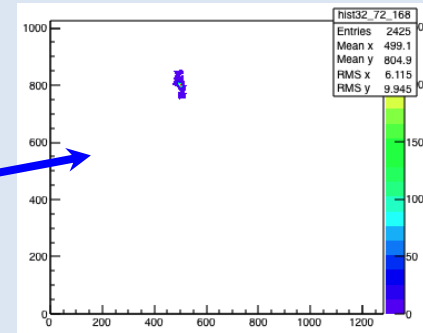
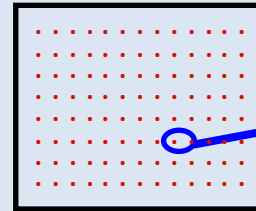
$$n(400\text{nm}) = [1 + 0.438\rho]^{1/2} = 1.0492$$



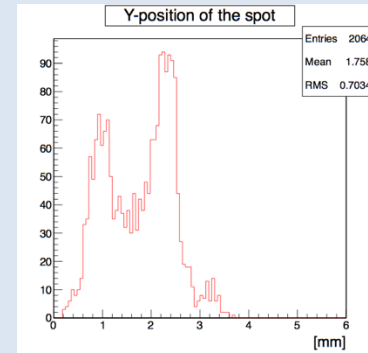
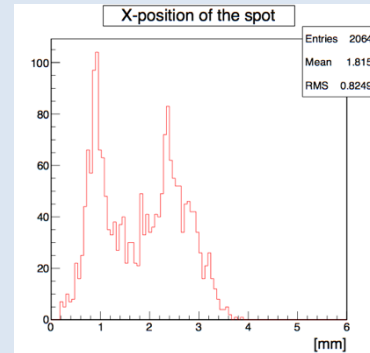
x-y axis movable table

CCD camera [ThorLabs DCU 224c]
- sensitive area [5.95-4.76 mm]
- resolution [1280-1024 pixels]
- pixel size 4.65 μm

Scan of aerogel surface

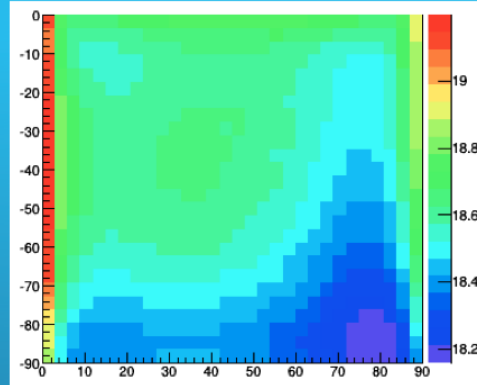


Distributions of X & Y positions of the spot

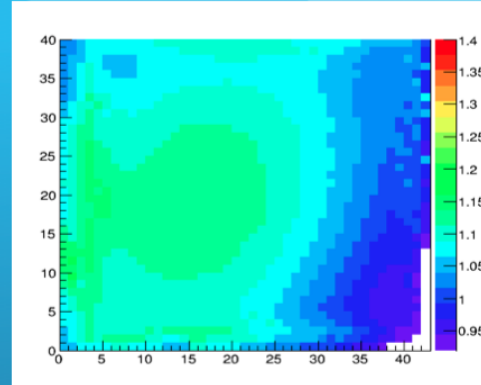


F
a
c
e
1

Touch
Machine



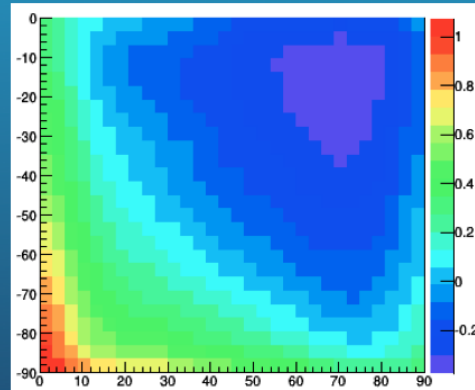
Laser
Setup



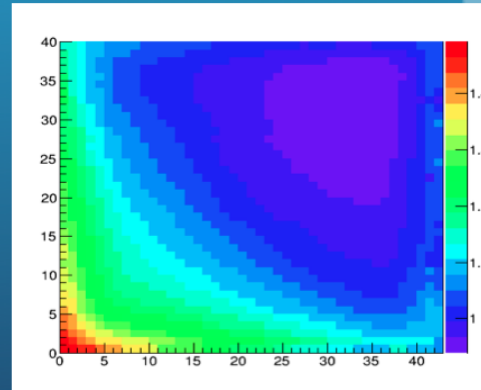
Possibility to derive the thickness profile

F
a
c
e
2

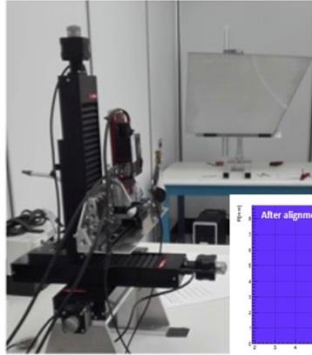
Touch
Machine



Laser
Setup



Main station at Duke-JLab developed as common facility (i.e. with existing INFN instrumentation)



D0 measurement:

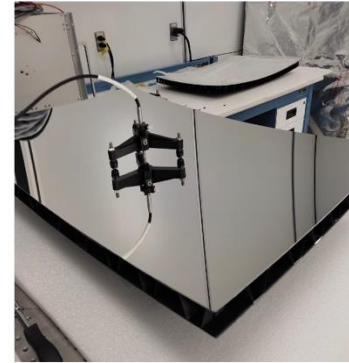
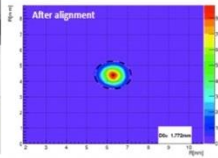
point-like image dimension

Global surface QA
Center of curvature

Stepper motor for alignment
and center scan

LED source (1 mm dia.)

CMOS camera



Reflectivity:

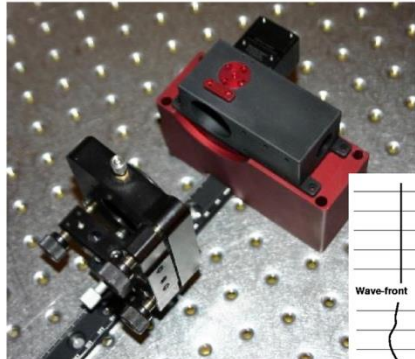
Portable instrument

Custom source + fiber distribution

Reference sensor

Compact spectrophotometer

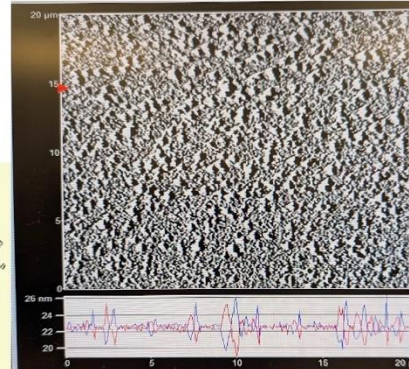
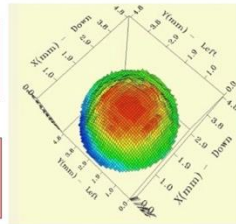
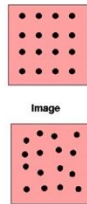
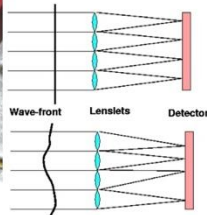
Various instrumentation for in-depth characterization is available at DUKE



Shack-Hartmann sensor:

reflected waveform analysis

Surface mapping



SMiF | SHARED MATERIALS
INSTRUMENTATION FACILITY

Access to a variety of instruments for
precision characterization of materials

AFM images of coated surface (SBU)
showing roughness of $< 100 \text{ nm}$

CFRP substrate mid-size (~50 cm side) demonstrator validated with lab tests before coating

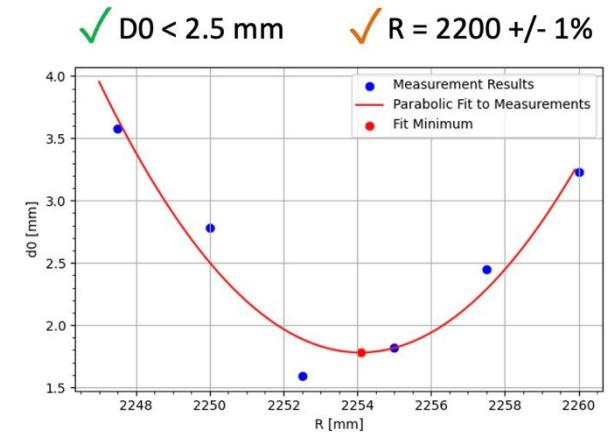
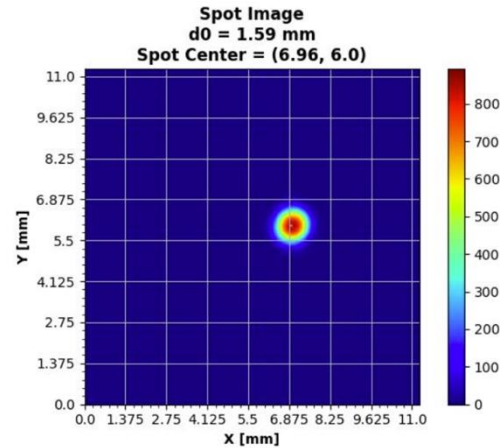
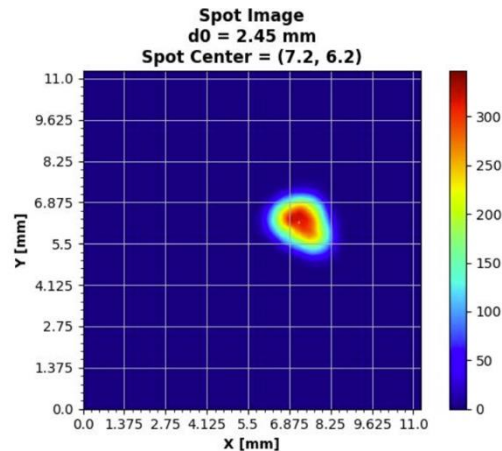
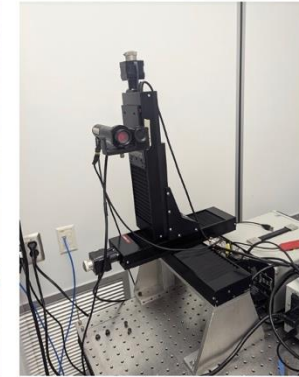
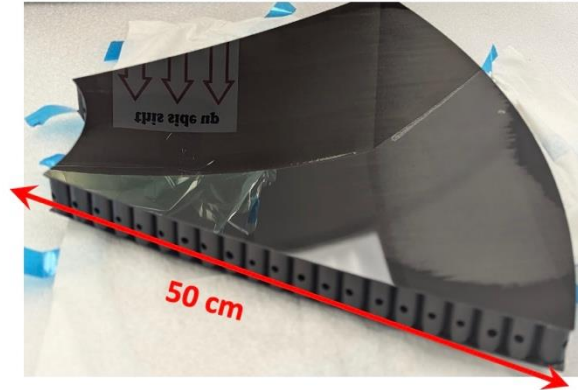
Annex C. Technical Requisite

Each spherical mirror is supplied with

- a spot-size measurement,
- a report on dimensions,
- no reflective coating.

The spherical mirrors are replicated from the same mandrel. The latter is realized with the novel cost-effective technology that reduces the mandrel total mass and cost. Each mirror fulfills the following optical quality specification:

- Radius within 1% of nominal RoC value
(the nominal RoC values is defined by the customer before production in the range 2000 mm \pm 10%),
- Roughness < 2 nm,
- Pointlike image spot size $D0 < 2.5$ mm,
- Compatibility with fluorocarbon gases (C_2F_6),
- Compatibility with SiO_2 reflecting coating.



Ongoing activities with possible synergies with pfRICH to be completed by 2026

Developing portable reflectivity test bench



Tripod head to scan spherical surface with proper alignment

